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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.

10/696,738

Applicant

Yager et al.

Filed

October 28, 2003

Title

Wavelength Tunable Surface Plasmon Resonance Sensor

Confirmation No.

6310

TC/A.U.

2877

Examiner'

Juan D. Valentin

Docket No.

128-02

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as Express Mail in an envelope

addressed to: Mail Stop Amendment,

Hon. Commissioner for Patents, PO Box 1450, Alexandria VA 22313-1450 EV 589 737 387 US

Date Aug Speaker

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner of Patents Mail Stop Amendment P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The Examiner is respectfully requested to consider the references, copies enclosed, which may qualify as prior art. For the Examiner's convenience, the references are listed on the attached Patent and Trademark Office form PTO-1449.

References listed in the PTO Form 1449 submitted herewith which do not specify the month of publication have a year of publication sufficiently earlier than the effective US filing date and any foreign priority date so that the particular month of publication is not an issue.

References known to the applicants have been listed on PTO-1449. That information is cited in a spirit of forthrightness and cooperation to enable the applicants to obtain that measure of protection for the invention to which there is entitlement. However, no representation is made that the listed art actually qualifies as prior art under the patent

statute and the mere use of PTO-1449 is not an admission that all listed references are prior art. No representation is made that applicants know of the best art.

It is believed that a fee of \$180.00 is due with the submission of this Information Disclosure Statement and a check in that amount is enclosed. If this amount submitted is incorrect, please charge any underpayment or credit any overpayment to Deposit Account No. 07-1969.

Respectfully submitted,

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Docket 128-02

ATTY DOCKET NO. 128-02 SERIAL NO. 10/696,738 FILING DATE 10/28/03

APPLICANT Yager GROUP 2877
Confirmation No. 6310

U.S. PATENT DOCUMENTS

Exmr. Initial	 Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclas s	Translation Yes/No
WO 02/059602 A2	08/01/2002	PCT	G01N	33/543	

NON-PATENT REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

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Brockman, J. M.et al. (2000), "Surface plasmon resonance imaging measurements of ultrathin organic films." <u>Annual Reviews of Physical Chemistry</u> 51 :41-63
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Form PTO 1449	T		
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APPLICANT Yager			GROUP 2877 Confirmation No. 6310

EXAMINER	microscopy." <u>Letters to Nature</u> 332 (14): 615-617. DATE CONSIDERED
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	resonance measurements of ultrathin films. 1. Angle shift and SPR imaging experiments," Anal. Chem. 71(18):3928-3934
	Nelson, B.P. et al., (1999), "Near-infrared surface plasmon
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***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

12/20/89